

# N-Channel Enhancement Mode Power MOSFET

### Description

The HM4490 uses advanced trench technology and design to provide excellent  $R_{DS(ON)}$  with low gate charge. It can be used in a wide variety of applications.

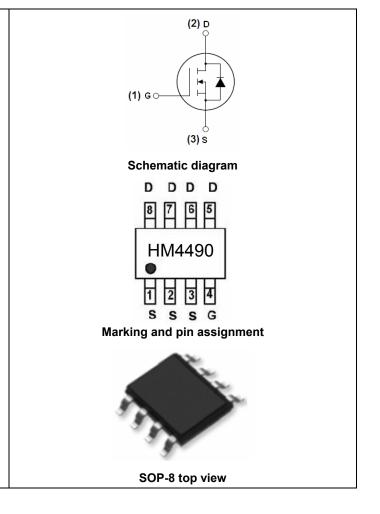
### **General Features**

- $V_{DS} = 200V, I_D = 3.9A$  $R_{DS(ON)} < 79m\Omega @ V_{GS} = 10V$  (Typ: 56m $\Omega$ )
- High density cell design for ultra low Rdson
- Fully characterized avalanche voltage and current
- Low gate to drain charge to reduce switching losses

#### Application

- Power switching application
- Hard switched and high frequency circuits
- Uninterruptible power supply

#### 100% ΔVds TESTED!



## Package Marking and Ordering Information

Device Marking	Device	Device Package	Reel Size	Tape width	Quantity
HM4490	HM4490	SOP-8	Ø330mm	12mm	2500 units

## Absolute Maximum Ratings (T<sub>A</sub>=25℃unless otherwise noted)

Parameter	Symbol	Limit	Unit
Drain-Source Voltage	Vds	200	V
Gate-Source Voltage	Vgs	±20	V
Drain Current-Continuous	Ι <sub>D</sub>	3.9	А
Drain Current-Continuous(T <sub>C</sub> =100℃)	I <sub>D</sub> (100℃)	3	A
Pulsed Drain Current	I <sub>DM</sub>	30	A
Maximum Power Dissipation	PD	3	W
Operating Junction and Storage Temperature Range	T <sub>J</sub> ,T <sub>STG</sub>	-55 To 150	°C

#### **Thermal Characteristic**

Thermal Resistance, Junction-to-Case <sup>(Note 2)</sup>	R <sub>θJC</sub>	41.7	°C <b>/W</b>
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# Electrical Characteristics (T<sub>A</sub>=25<sup>°</sup>C unless otherwise noted)

Parameter	Symbol	Condition	Min	Тур	Мах	Unit
Off Characteristics	· · ·					
Drain-Source Breakdown Voltage	BV <sub>DSS</sub>	V <sub>GS</sub> =0V I <sub>D</sub> =250µA	200	215	-	V
Zero Gate Voltage Drain Current	I <sub>DSS</sub>	V <sub>DS</sub> =200V,V <sub>GS</sub> =0V	-	-	1	μA
Gate-Body Leakage Current	I <sub>GSS</sub>	$V_{GS}$ =±20V, $V_{DS}$ =0V	-	-	±100	nA
On Characteristics (Note 3)	· · ·		•			
Gate Threshold Voltage	V <sub>GS(th)</sub>	$V_{DS}=V_{GS}$ , $I_{D}=250\mu A$	2	3	4	V
Drain-Source On-State Resistance	R <sub>DS(ON)</sub>	$V_{GS}$ =10V, I <sub>D</sub> =3.7A	-	56	79	mΩ
Forward Transconductance	<b>G</b> FS	V <sub>DS</sub> =50V,I <sub>D</sub> =3.9A	7	-	-	S
Dynamic Characteristics (Note4)	· · ·		•		·	
Input Capacitance	C <sub>lss</sub>			4200		PF
Output Capacitance	C <sub>oss</sub>	V <sub>DS</sub> =25V,V <sub>GS</sub> =0V, F=1.0MHz		163		PF
Reverse Transfer Capacitance	C <sub>rss</sub>			75		PF
Switching Characteristics (Note 4)	· · ·		•			
Turn-on Delay Time	t <sub>d(on)</sub>		-	15	-	nS
Turn-on Rise Time	tr	V <sub>DD</sub> =100V,I <sub>D</sub> =2.2A	-	13	-	nS
Turn-Off Delay Time	t <sub>d(off)</sub>	$V_{GS}$ =10V, $R_{GEN}$ =6.5 $\Omega$	-	26	-	nS
Turn-Off Fall Time	t <sub>f</sub>		-	14	-	nS
Total Gate Charge	Qg	V -100V/L -2.2A	-	38	-	nC
Gate-Source Charge	Q <sub>gs</sub>	$V_{DS}$ =100V,I <sub>D</sub> =2.2A,	-	9	-	nC
Gate-Drain Charge	Q <sub>gd</sub>	V <sub>GS</sub> =10V	-	15	-	nC
Drain-Source Diode Characteristics	· · ·					
Diode Forward Voltage (Note 3)	V <sub>SD</sub>	V <sub>GS</sub> =0V,I <sub>S</sub> =3.7A	-	-	1.2	V
Diode Forward Current (Note 2)	I <sub>S</sub>		-	-	4	А

Notes:

1. Repetitive Rating: Pulse width limited by maximum junction temperature.

**2.** Surface Mounted on FR4 Board,  $t \le 10$  sec.

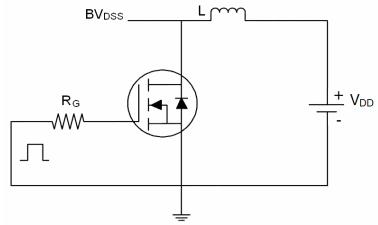
**3.** Pulse Test: Pulse Width  $\leq$  300µs, Duty Cycle  $\leq$  2%.

4. Guaranteed by design, not subject to production

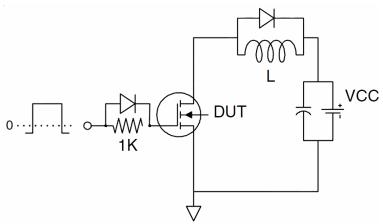


# **Test Circuit**

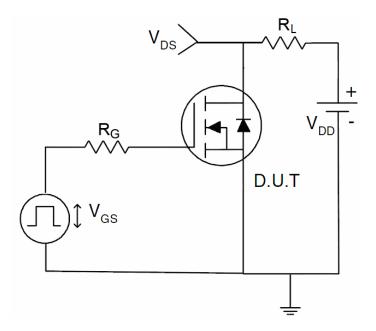
1) E<sub>AS</sub> test Circuit



## 2) Gate charge test Circuit

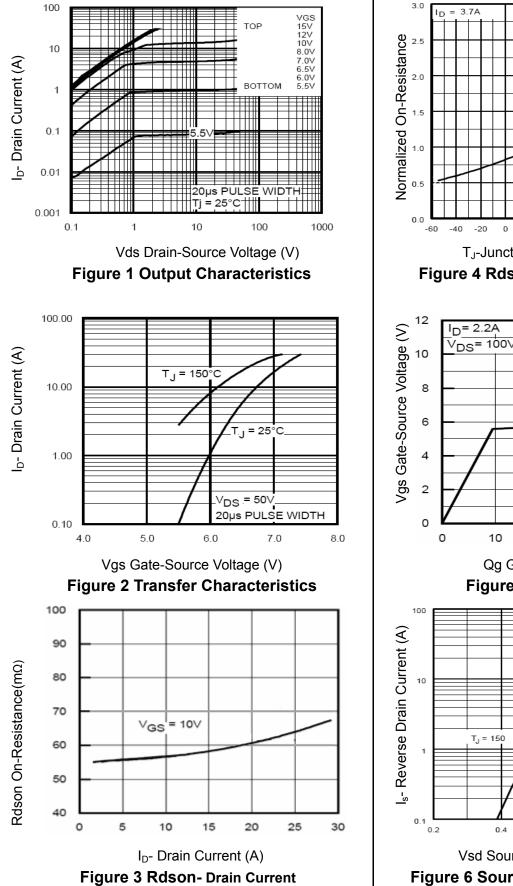


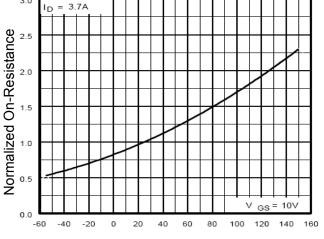
3) Switch Time Test Circuit





# **Typical Electrical and Thermal Characteristics (Curves)**





 $\mathsf{T}_{\mathsf{J}} ext{-}\mathsf{Junction}$  Temperature(°C)

Figure 4 Rdson-JunctionTemperature

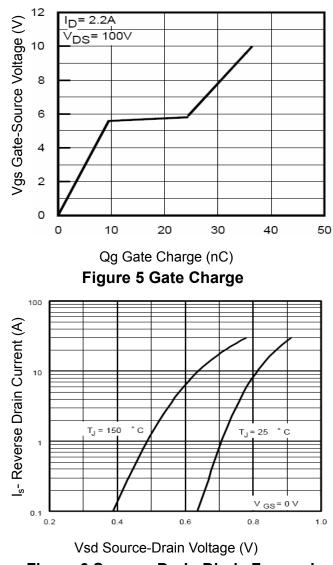
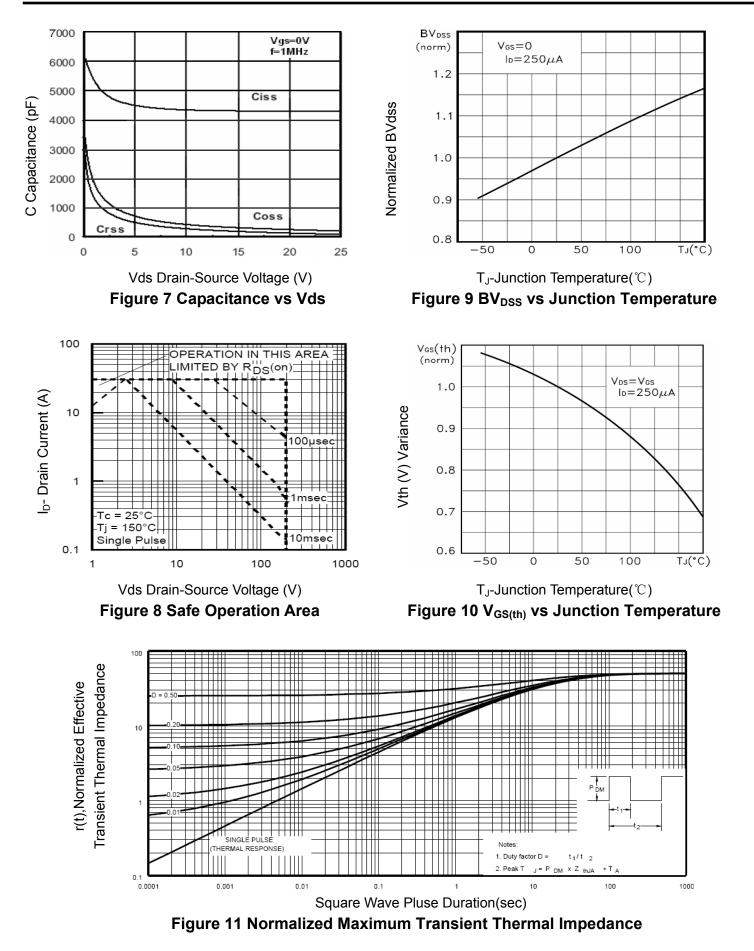


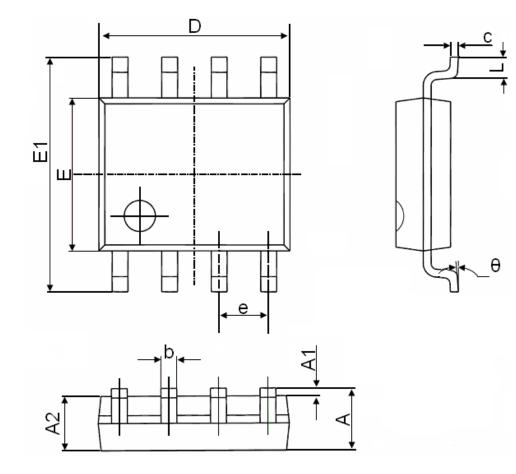
Figure 6 Source- Drain Diode Forward







# **SOP-8 Package Information**



Symbol	Dimensions	In Millimeters	Dimensions In Inches		
	Min.	Max.	Min.	Max.	
A	1.350	1.750	0.053	0.069	
A1	0.100	0.250	0.004	0.010	
A2	1.350	1.550	0.053	0.061	
b	0.330	0.510	0.013	0.020	
с	0.170	0.250	0.006	0.010	
D	4.700	5.100	0.185	0.200	
E	3.800	4.000	0.150	0.157	
E1	5.800	6.200	0.228	0.244	
e	1.270(BSC)		0.050	(BSC)	
L	0.400	1.270	0.016	0.050	
θ	0°	8°	0°	8°	



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